

# 1200V thinQ!<sup>™</sup> SiC Schottky Diode

### Features:

- Revolutionary Semiconductor Material -Silicon Carbide
- Switching Behaviour Benchmark
- No Reverse Recovery / No Forward Recovery
- Temperature Independent Switching Behaviour
- Qualified According to JEDEC<sup>1)</sup> Based on Target Applications

### Applications:

- Motor Drives / Solar Inverters
- High Voltage CCM PFC
- Switch Mode Power Supplies
- High Voltage Multipliers

Chip Type	V <sub>BR</sub>	l <sub>F</sub>	Die Size	Package
IDC08S120	1200V	7.5A	2.012 x 2.012 mm <sup>2</sup>	sawn on foil

## **MECHANICAL PARAMETERS**

Raster size	2.012 x 2.012				
Anode pad size	1.476 x 1.476	mm <sup>2</sup>			
Area total / active	4.05 / 3				
Thickness	362	μm			
Wafer size	75	mm			
Flat position	0	deg			
Max. possible chips per wafer	901 pcs				
Passivation frontside	Photoimide				
Pad metal	3200 nm Al				
Backside metal	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding				
Die bond	Electrically conductive glue or solder				
Wire bond	AI, ≤ 350µm				
Reject ink dot size	$arnothing \ge 0.3 \ \text{mm}$				
Recommended storage environment	Store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C				





## **ELECTRICAL PARAMETERS**

#### **Maximum Ratings**

Parameter	Symbol	Condition	Value	Unit	
Repetitive peak reverse voltage	V <sub>RRM</sub>	<i>T</i> j=25 ℃	1200	v	
DC blocking voltage	V <sub>DC</sub>		1200	Ň	
Continuous forward current, limited by T <sub>jmax</sub>	I <sub>F</sub>		7.5		
Surge non repetitive forward current,	,	$T_{\rm C} = 25^{\circ} C, \ t_{\rm P} = 10 \ ms$	39		
sine halfwave	I <sub>F,SM</sub>	$T_C = 150^{\circ}C, t_P = 10 ms$	33	A	
Repetitive peak forward current, limited by thermal resistance R <sub>th</sub>	I <sub>F,RM</sub>	$T_C = 100^{\circ}C, \ T_j = 150^{\circ}C, \ D=0.1$	32		
Non-repetitive peak forward current	I <sub>F,max</sub>	T <sub>C</sub> =25°C, t <sub>P</sub> =10μs	160		
i <sup>2</sup> t value	$\int i^2 dt$	$T_{C} = 25^{\circ}C, t_{P} = 10 ms$	7	A <sup>2</sup> s	
		$T_{C} = 150 ^{\circ}C, t_{P} = 10  ms$	5		
Operating junction and storage temperature range	$T_{j}$ , $T_{stg}$		-55+175	°C	

### Static Characteristics (tested on wafer)

Parameter	Symbol	Conditions		Unit		
		Conditions	min.	Тур.	max.	
Reverse current	I <sub>R</sub>	V <sub>R</sub> =1200V, T <sub>j</sub> =25°C		8	180	μA
Diode forward voltage	V <sub>F</sub>	I <sub>F</sub> =7.5A, T <sub>j</sub> =25°C		1.6	1.8	V

### Static Characteristics (not subject to production test - verified by design / characterization)

Parameter	Symbol	Conditions		Unit		
		Conditions	min.	Тур.	max.	
Reverse current	I <sub>R</sub>	V <sub>R</sub> =1200V, T <sub>j</sub> =150°C		30	1000	μA
Diode forward voltage	V <sub>F</sub>	I <sub>F</sub> =7.5A, T <sub>j</sub> =150°C		2.5	3	V



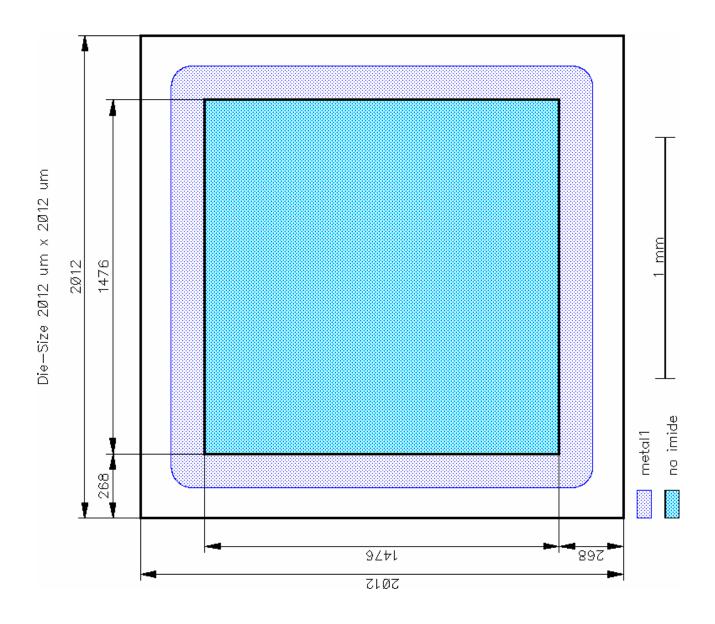
Parameter	Symbol	Conditions		Value			Unit
	Cymbol			min.	Тур.	max.	
Total capacitive charge <sup>3)</sup>	Q <sub>C</sub>	$I_F <= I_{F,max}$ di/dt = 200 A/ms $V_R = 1200 V$	T <sub>j</sub> =150 °C		27		nC
Switching time <sup>2)</sup>	t <sub>c</sub>		T <sub>j</sub> =150 °C			<10	ns
Total capacitance	с	f=1MHz	$V_R = 1V$		380		
			V <sub>R</sub> =300V		30		pF
			V <sub>R</sub> =600V		27		

### Dynamic Characteristics (not subject to production test - verified by design / characterization)

<sup>1)</sup> J-STD20 and JESD22 <sup>2)</sup> t<sub>c</sub> is the time constant for the capacitive displacement current waveform (independent from T<sub>j</sub>, I<sub>LOAD</sub> and di/dt), different from t<sub>rr</sub>, which is dependent on T<sub>j</sub>, I<sub>LOAD</sub>, di/dt. No reverse recovery time constant t<sub>rr</sub> due to absence of minority carrier inject. <sup>3)</sup> Only capacitive charge occurring, guaranteed by design (independent from T<sub>j</sub>, I<sub>LOAD</sub> and di/dt).



**CHIP DRAWING** 





### FURTHER ELECTRICAL CHARACTERISTICS

This chip data sheet refers to the device data sheet

INFINEON TECHNOLOGIES

IDH08S120

#### **Description:**

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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